

Application/Control No.	Applicant(s)/Patent under Reexamination
10/816,178	JOHNSON ET AL.
Examiner	Art Unit
Hai L. Nguyen	2816

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Class	Subclass	Date	Examiner
327	2,3,7,12	5/24/2005	HLN
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331	25,DIG.2	V	<b>V</b> .
Update	Search	9/30/2005	HLN
327	5	9/30/2005	HLN
Update	Search	4/12/2006	HLN
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INT	NTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
See	Printout	4/13/2006	HLN
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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